

May 2001

FQT7N10L

100V LOGIC N-Channel MOSFET

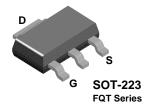
General Description

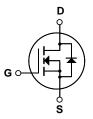
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as high efficiency switching DC/DC converters, and DC motor control.

Features

- 1.7A, 100V, $R_{DS(on)}$ = 0.35 Ω @V_{GS} = 10 V Low gate charge (typical 4.6 nC)
- Low Crss (typical 12 pF)
- · Fast switching
- · Improved dv/dt capability
- · Low level gate drive requirments allowing direct operationfrom logic drives





Absolute Maximum Ratings T_C = 25°C unless otherwise noted

	U			
Symbol	Parameter		FQT7N10L	Units
V _{DSS}	Drain-Source Voltage		100	V
I _D	Drain Current - Continuous (T _C = 25°C) - Continuous (T _C = 70°C)		1.7	Α
			1.36	А
I _{DM}	Drain Current - Pulsed	(Note 1)	6.8	Α
V _{GSS}	Gate-Source Voltage		± 20	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	50	mJ
I _{AR}	Avalanche Current	(Note 1)	1.7	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	0.2	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0	V/ns
P_{D}	Power Dissipation (T _C = 25°C)		2.0	W
	- Derate above 25°C		0.016	W/°C
T_J , T_{STG}	Operating and Storage Temperature Range		-55 to +150	°C
TL	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C
.r			300	

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		62.5	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μA, Referenced to 25	°C	0.1		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 100 V, V _{GS} = 0 V			1	μА
		V _{DS} = 80 V, T _C = 125°C			10	μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
On Cha	racteristics		·			
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	1.0		2.0	V
R _{DS(on)}	Static Drain-Source	$V_{GS} = 10 \text{ V}, I_D = 0.85 \text{ A}$			0.35	
(On)	On-Resistance	$V_{GS} = 5 \text{ V}, I_D = 0.85 \text{ A}$		0.275 0.300	0.38	()
9FS	Forward Transconductance	$V_{DS} = 30 \text{ V}, I_{D} = 0.85 \text{ A}$ (Note	e 4)	2.75		S
Dvnam	ic Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$		220	290	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		55	72	pF
C _{rss}	Reverse Transfer Capacitance			12	15	pF
Switchi	ing Characteristics					
t _{d(on)}	Turn-On Delay Time	V 50.V I 70.A		9	30	ns
t _r	Turn-On Rise Time	$V_{DD} = 50 \text{ V}, I_{D} = 7.3 \text{ A},$ $R_{G} = 25 \Omega$		100	210	ns
t _{d(off)}	Turn-Off Delay Time	NG = 23 22		17	45	ns
t _f	Turn-Off Fall Time	(Note	4, 5)	50	110	ns
Q _q	Total Gate Charge	$V_{DS} = 80 \text{ V}, I_{D} = 7.3 \text{ A},$		4.6	6.0	nC
Q _{gs}	Gate-Source Charge	$V_{GS} = 5 \text{ V}$		1.0		nC
Q _{gd}	Gate-Drain Charge	(Note	1, 5)	2.6		nC
			1	l .		Į.
Drain-S	Source Diode Characteristics at				1.7	Α
I _{SM}	Maximum Continuous Drain-Source Diode Forward Current Maximum Pulsed Drain-Source Diode Forward Current				6.8	A
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 1.7 A			1.5	V
	Diani-Source Diode Forward voltage		-			V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 7.3 \text{ A},$		70		ns

- Notes:
 1. Repetitive Rating : Pulse width limited by maximum junction temperature
 2. L = 26mH, I_{AS} = 1.7A, V_{DD} = 25V, R_G = 25 Ω , Starting T_J = 25°C
 3. I_{SD} \leq 7.3A, di/dt \leq 300A/ μ s, V_{DD} \leq BV_{DSS}, Starting T_J = 25°C
 4. Pulse Test : Pulse width \leq 300 μ s, Duty cycle \leq 2%
 5. Essentially independent of operating temperature

Typical Characteristics

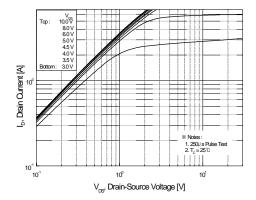


Figure 1. On-Region Characteristics

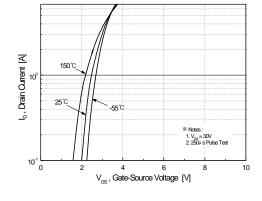


Figure 2. Transfer Characteristics

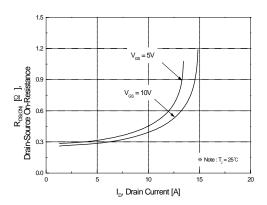


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

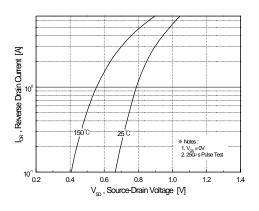


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

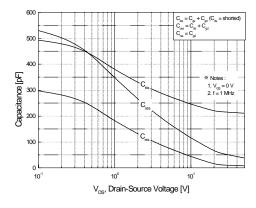


Figure 5. Capacitance Characteristics

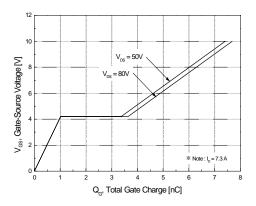


Figure 6. Gate Charge Characteristics

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Typical Characteristics (Continued)

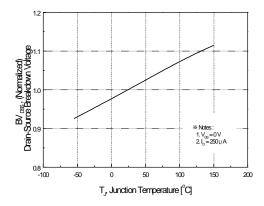
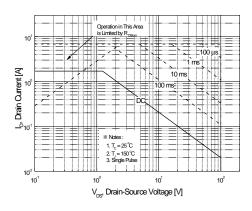


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



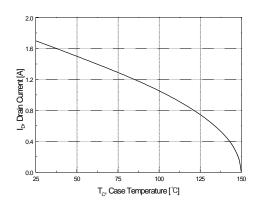


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

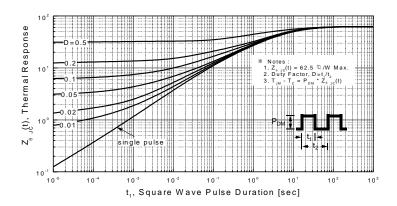
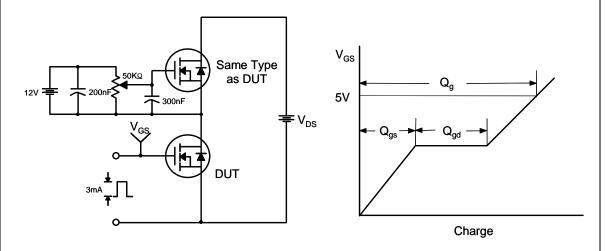


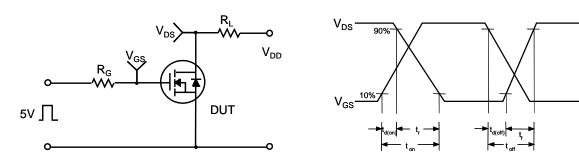
Figure 11. Transient Thermal Response Curve

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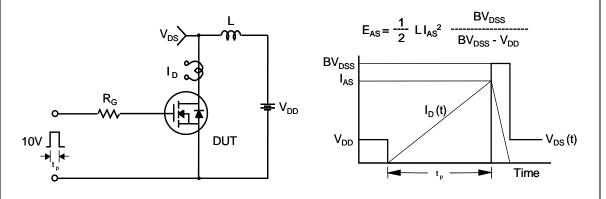
Gate Charge Test Circuit & Waveform



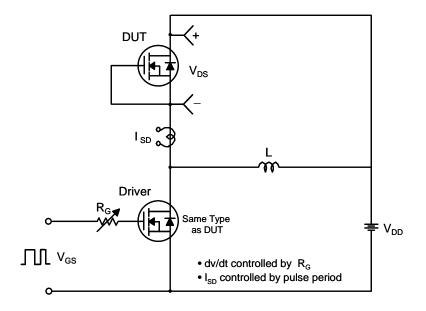
Resistive Switching Test Circuit & Waveforms

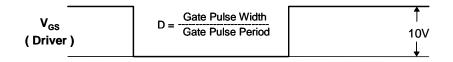


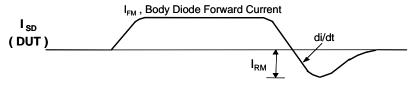
Unclamped Inductive Switching Test Circuit & Waveforms



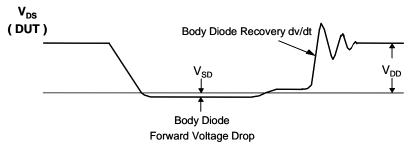
Peak Diode Recovery dv/dt Test Circuit & Waveforms





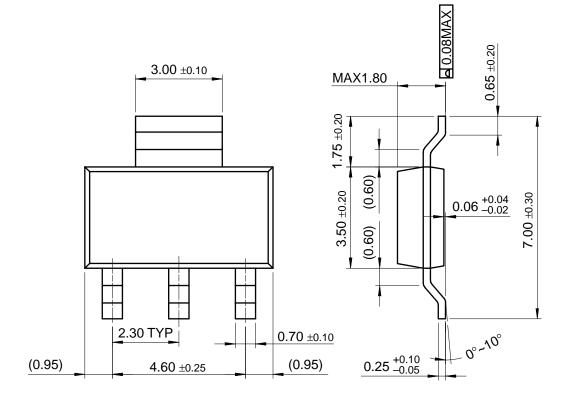


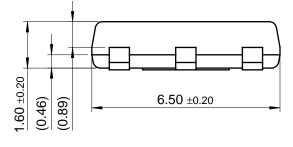
Body Diode Reverse Current





SOT-223





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